
HB56U232 Series

2,097,152-word $\times$ 32-bit High Density Dynamic RAM Module

HITACHI

Description

The HB56U232 is a 2 M $\times$ 32 dynamic RAM module, mounted 16 pieces of 4-Mbit DRAM (HM514405CS) sealed in SOJ package.

An outline of the HB56U232 is 72-pin single in-line package. Therefore, the HB56U232 makes high density mounting possible without surface mount technology. The HB56U232 provides common data inputs and outputs. Decoupling capacitors are mounted beneath each SOJ on the module board.

The HB56U232 offers Extended Data Out (EDO) page mode as a high speed access mode.

Features

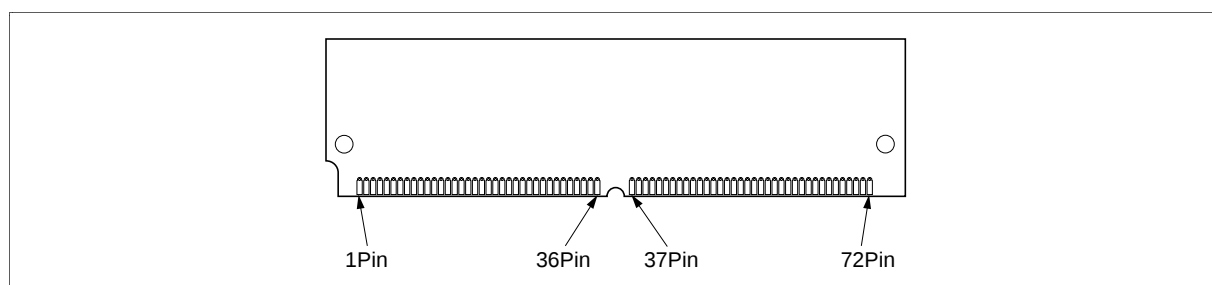
- 72-pin single in-line package
 - Lead pitch: 1.27 mm
- Single 5 V ($\pm 5\%$) supply
- High speed
 - Access time: $t_{\text{RAC}} = 60/70$ ns (max)
- Low power dissipation
 - Active mode: 4.83/4.41 W (max)
 - Standby mode: 168 mW (max)
- EDO page mode capability
- 1,024 refresh cycles: 16 ms
- 2 variations of refresh
 - $\overline{\text{RAS}}$ -only refresh
 - $\overline{\text{CAS}}$ -before- $\overline{\text{RAS}}$ refresh
- TTL compatible

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Ordering Information

Type No.	Access time	Package	Contact pad
HB56U232B-6C	60 ns	72-pin SIP socket type	Gold
HB56U232B-7C	70 ns		
HB56U232SB-6C	60 ns	72-pin SIP socket type	Solder
HB56U232SB-7C	70 ns		

Pin Arrangement



Pin No.	Pin Name	Pin No.	Pin Name	Pin No.	Pin Name	Pin No.	Pin Name
1	V _{SS}	19	NC	37	NC	55	DQ11
2	DQ0	20	DQ4	38	NC	56	DQ27
3	DQ16	21	DQ20	39	V _{SS}	57	DQ12
4	DQ1	22	DQ5	40	CAS0	58	DQ28
5	DQ17	23	DQ21	41	CAS2	59	V _{CC}
6	DQ2	24	DQ6	42	CAS3	60	DQ29
7	DQ18	25	DQ22	43	CAS1	61	DQ13
8	DQ3	26	DQ7	44	RAS0	62	DQ30
9	DQ19	27	DQ23	45	RAS1	63	DQ14
10	V _{CC}	28	A7	46	NC	64	DQ31
11	NC	29	NC	47	WE	65	DQ15
12	A0	30	V _{CC}	48	NC	66	PD5
13	A1	31	A8	49	DQ8	67	PD1
14	A2	32	A9	50	DQ24	68	PD2
15	A3	33	RAS3	51	DQ9	69	PD3
16	A4	34	RAS2	52	DQ25	70	PD4
17	A5	35	NC	53	DQ10	71	NC
18	A6	36	NC	54	DQ26	72	V _{SS}

Pin Description

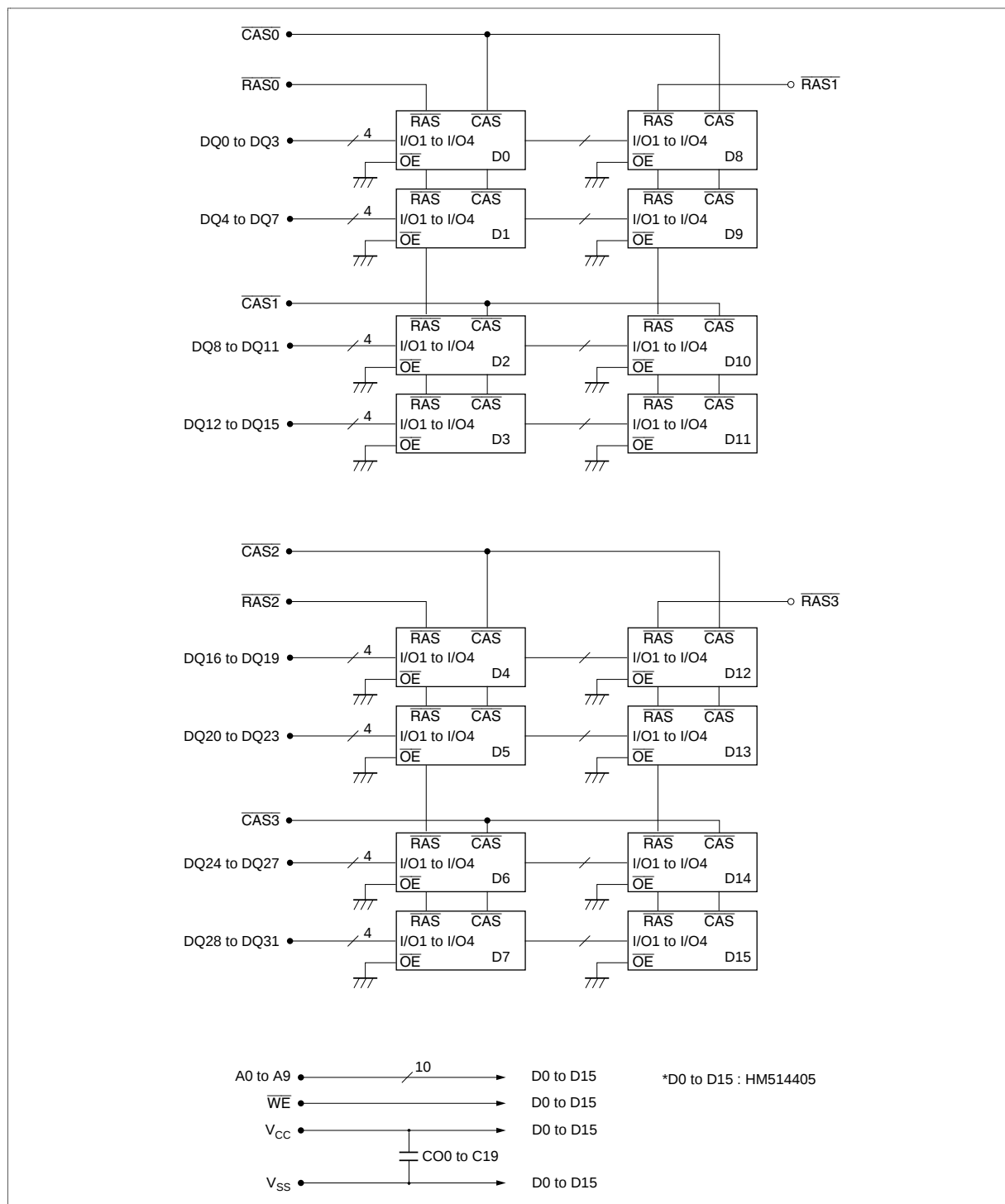
Pin Name	Function
A0 – A9	Address Input: A0 – A9 Row address: A0 – A9 Column address: A0 – A9 Refresh address: A0 – A9
DQ0 – DQ31	Data-in/Data-out
$\overline{\text{CAS0}}$ to $\overline{\text{CAS3}}$	Column Address Strobe
$\overline{\text{RAS0}}$ to $\overline{\text{RAS3}}$	Row Address Strobe
$\overline{\text{WE}}$	Read/Write Enable
V_{CC}	Power Supply (+5 V)
V_{SS}	Ground
PD1 to PD4	Presence detect pin
PD5	Presence detect pin for EDO
NC	No Connection

Presence Detect Pin Arrangement

Pin No.	Pin Name	Function	
		60 ns	70 ns
66	PD5	V_{SS}	V_{SS}
67	PD1	NC	NC
68	PD2	NC	NC
69	PD3	NC	V_{SS}
70	PD4	NC	NC

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Block Diagram



Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Voltage on any pin relative to V_{SS}	V_T	–1.0 to +7.0	V
Supply voltage relative to V_{SS}	V_{CC}	–1.0 to +7.0	V
Short circuit output current	I_{out}	50	mA
Power dissipation	P_t	8	W
Operating temperature	T_{opr}	0 to +70	°C
Storage temperature	T_{stg}	–55 to +125	°C

Recommended DC Operating Conditions ($T_a = 0$ to +70°C)

Parameter	Symbol	Min	Typ	Max	Unit	Note
Supply voltage	V_{SS}	0	0	0	V	
	V_{CC}	4.75	5.0	5.25	V	1
Input high voltage	V_{IH}	2.4	—	5.5	V	1
Input low voltage	V_{IL}	–1.0	—	0.8	V	1

Note: 1. All voltage referred to V_{SS} .

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DC Characteristics ($T_a = 0$ to $+70^\circ\text{C}$, $V_{CC} = 5\text{ V} \pm 5\%$, $V_{SS} = 0\text{ V}$)

		HB56U232						
		60 ns		70 ns				
Parameter	Symbol	Min	Max	Min	Max	Unit	Test conditions	Notes
Operating current	I _{CC1}	—	920	—	840	mA	t _{RC} = min	1, 2
Standby current	I _{CC2}	—	32	—	32	mA	TTL interface RAS, CAS = V _{IH} Dout = High-Z	
		—	16	—	16	mA	CMOS interface RAS, CAS ≥ V _{CC} − 0.2 V Dout = High-Z	
RAS-only refresh current	I _{CC3}	—	920	—	840	mA	t _{RC} = min	2
Standby current	I _{CC5}	—	80	—	80	mA	RAS = V _{IH} , CAS = V _{IL} Dout = enable	1
CAS-before-RAS refresh current	I _{CC6}	—	920	—	840	mA	t _{RC} = min	
EDO page mode current	I _{CC4}	—	1080	—	1000	mA	t _{HPC} = min	1, 3
Input leakage current	I _{LI}	−10	10	−10	10	μA	0 V ≤ Vin ≤ 7.0 V	
Output leakage current	I _{LO}	−10	10	−10	10	μA	0 V ≤ Vout ≤ 7.0 V Dout = disable	
Output high voltage	V _{OH}	2.4	V _{CC}	2.4	V _{CC}	V	High Iout = −2 mA	
Output low voltage	V _{OL}	0	0.4	0	0.4	V	Low Iout = 2 mA	

Notes: 1. I_{CC} depends on output load condition when the device is selected, I_{CC} max is specified at the output open condition.

2. Address can be changed once or less while $\overline{RAS} = V_{IL}$.

3. Address can be changed once or less while $\overline{CAS} = V_{IH}$.

Capacitance ($T_a = 25^\circ\text{C}$, $V_{CC} = 5\text{ V} \pm 5\%$)

Parameter	Symbol	Typ	Max	Unit	Notes
Input capacitance (Address)	C_{I1}	—	95	pF	1
Input capacitance ($\overline{WE}$)	C_{I2}	—	127	pF	1
Input capacitance ($\overline{RAS}$)	C_{I3}	—	43	pF	1
Input capacitance ($\overline{CAS}$)	C_{I4}	—	43	pF	1
I/O capacitance (DQ0 to 31)	$C_{I/O}$	—	29	pF	1, 2

Notes: 1. Capacitance measured with Boonton Meter or effective capacitance measuring method.

2. $\overline{RAS}$ and $\overline{CAS} = V_{IH}$ to disable Dout.

